

TEST REPORT

Applicant: Fibocom Wireless Inc.
Address: 1101, Tower A, Building 6, Shenzhen International
Innovation Valley, Dashi 1st Rd, Nanshan,
Shenzhen, China
Equipment Type: LTE Module
Model Name: MG661-LA
Brand Name: Fibocom
FCC ID ZMOMG661LA
Test Standard: 47 CFR Part 15 Subpart B
ANSI C63.4-2014
Sample Arrival Date: Feb. 07, 2025
Test Date: Feb. 10, 2025 - Feb. 12, 2025
Date of Issue: Mar. 12, 2025

ISSUED BY:

Shenzhen BALUN Technology Co., Ltd.

Tested by: Qiu Yongjing **Checked by:** Liu Zhenxiang **Approved by:** Tolan Tu
(Testing Director)

Qiu Yongjing

Liu Zhenxiang

Tolan Tu

Revision History

Version	Issue Date	Revisions
<u>Rev. 01</u>	<u>Mar. 04, 2025</u>	<u>Initial Issue</u>
<u>Rev. 02</u>	<u>Mar. 12, 2025</u>	<u>Update EUT external photo names.</u>

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1 GENERAL INFORMATION

1.1 Test Laboratory

Name	Shenzhen BALUN Technology Co., Ltd.
Address	Block B, 1/F, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China
Phone Number	+86 755 6685 0100

1.2 Test Location

Name	Shenzhen BALUN Technology Co., Ltd.
Location	☒ Block B, 1/F, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China
	☐ 1/F, Building B, Ganghongji High-tech Intelligent Industrial Park, No. 1008, Songbai Road, Yangguang Community, Xili Sub-district, Nanshan District, Shenzhen, Guangdong Province, P. R. China
Accreditation Certificate	The laboratory is a testing organization accredited by FCC as a accredited testing laboratory. The designation number is CN1196.

2 PRODUCT INFORMATION

2.1 Applicant Information

Applicant	Fibocom Wireless Inc.
Address	1101, Tower A, Building 6, Shenzhen International Innovation Valley, Dashu 1st Rd, Nanshan, Shenzhen, China

2.2 Manufacturer Information

Manufacturer	Fibocom Wireless Inc.
Address	1101, Tower A, Building 6, Shenzhen International Innovation Valley, Dashu 1st Rd, Nanshan, Shenzhen, China

2.3 General Description for Equipment under Test (EUT)

EUT Name	LTE Module
Model Name Under Test	MG661-LA
Series Model Name	N/A
Description of Model name differentiation	N/A
Hardware Version	V1.2
Software Version	16009.1000.00.01.86.03
Dimensions (Approx.)	N/A
Weight (Approx.)	N/A

2.4 Ancillary Equipment

Note: Not applicable.

2.5 Technical Information

Network and Wireless connectivity	4G Network LTE FDD Band 2/4/5/7/66
Classification of equipment	Class B
The highest internal frequency of EUT	2690MHz

3 SUMMARY OF TEST RESULTS

3.1 Test Standards

No.	Identity	Document Title
1	47 CFR Part 15 Subpart B	Unintentional Radiators
2	ANSI C63.4-2014	American National Standard for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40 GHz

3.2 Verdict

No.	Description	FCC Rule	Test Verdict	Remark
1	Radiated Emission	15.109	Pass	--
2	Conducted Emission, AC Ports	15.107	Pass	--

Note: Compared with the EUT in test report BL-SZ2360790-401, the EUT in this report shows the following differences:

1. The software has been updated to meet the market demand. The RF performance is not affected.
2. Added six types of antennas.

The other hardware circuits and software are the same as the EUT mentioned in test report BL-SZ2360790-401.

Therefore, based on the above differences, just Radiated Emission was retested in this report, others test data please refer to report BL-SZ2360790-401, which was issued by Shenzhen BALUN Technology Co., Ltd. on Jul. 31, 2023.

3.3 Test Uncertainty

The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

Measurement	Value
Radiated emissions (30 MHz-1 GHz)-966#2	4.4 dB
Radiated emissions (1 GHz-18 GHz)-966#2	5.0 dB

4 GENERAL TEST CONFIGURATIONS

4.1 Test Enclosure List

Description	Manufacturer	Model	Serial No.	Length	Description	Use
Adapter	N/A	N/A	N/A	N/A	N/A	☒
USB Cable	N/A	N/A	N/A	N/A	N/A	☒

4.2 Test Configurations

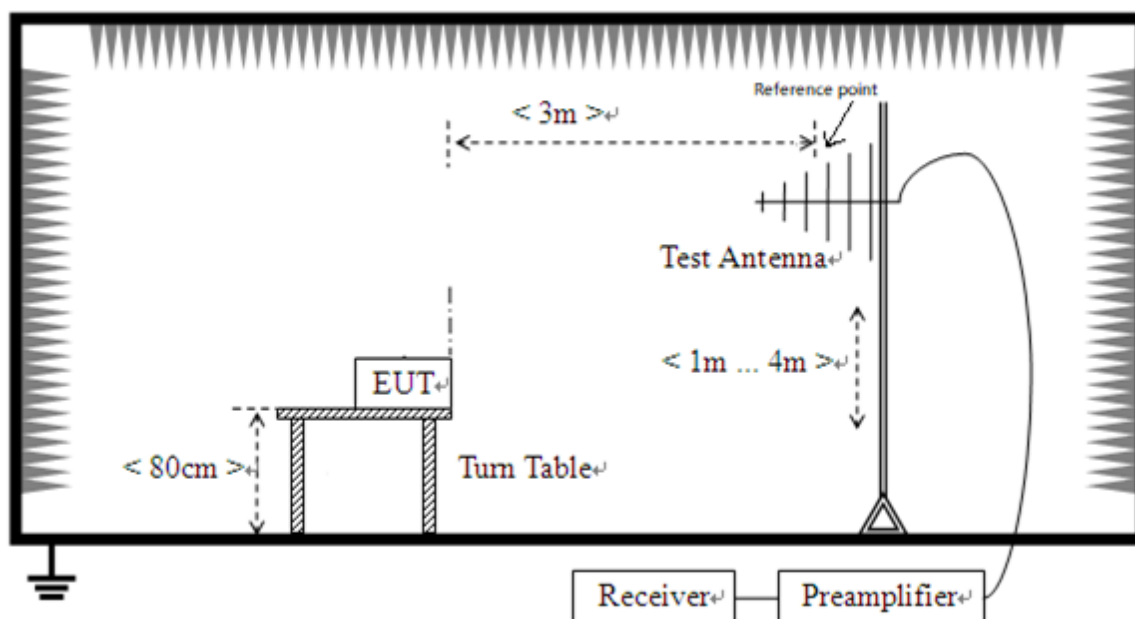
All test modes of EUT are listed in the table below.

Test Mode Configuration	Description
Mode 1	<u>The LTE Band 5 RX Test Mode</u> LTE Band 5 RX + EUT + Adapter + USB Cable + ANT(F-0Y-31-0116-001-K0)
Mode 2	<u>The LTE Band 5 RX Test Mode</u> LTE Band 5 RX + EUT + Adapter + USB Cable + ANT(F-0Y-31-0116-002-K0)
Mode 3	<u>The LTE Band 5 RX Test Mode</u> LTE Band 5 RX + EUT + Adapter + USB Cable + ANT(TQX-071427HK22)
Mode 4	<u>The LTE Band 5 RX Test Mode</u> LTE Band 5 RX + EUT + Adapter + USB Cable + ANT(KIT-KIT-HK23-PT24-4G)
Mode 5	<u>The LTE Band 5 RX Test Mode</u> LTE Band 5 RX + EUT + Adapter + USB Cable + ANT(F-0Y-31-0166-001-K0)
Mode 6	<u>The LTE Band 5 RX Test Mode</u> LTE Band 5 RX + EUT + Adapter + USB Cable + ANT(TQX-071427HK22-L)

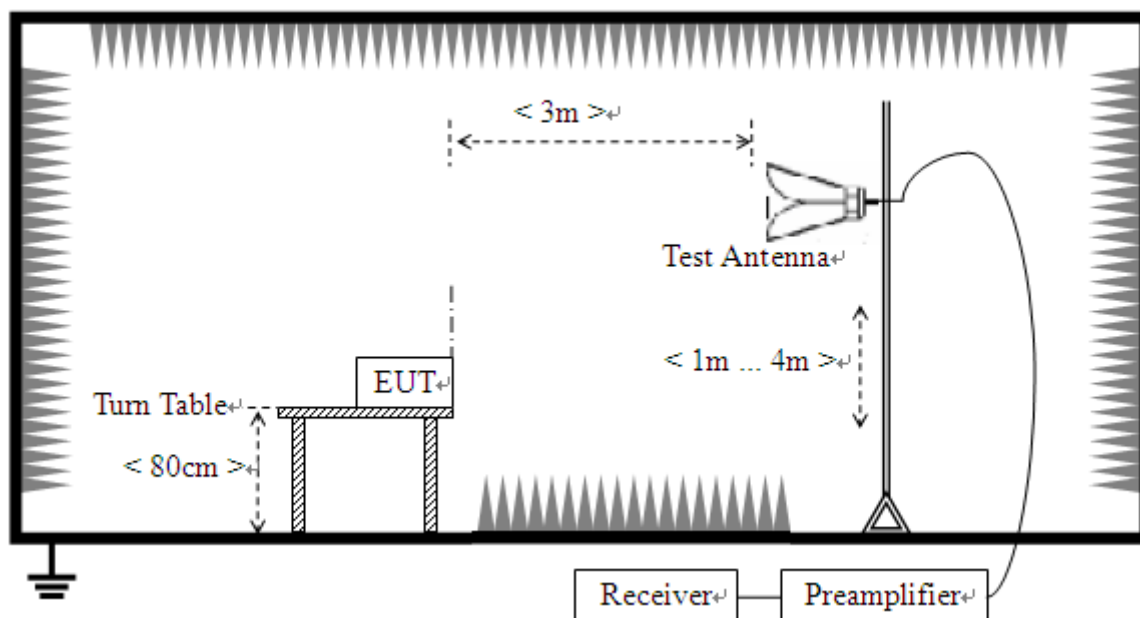
Test Case	Test Mode Configuration	Worst Mode
Radiated Emission	Mode 1~Mode 6	3
Conducted Emission, AC Ports	Mode 1~Mode 6	3
Note: All operation modes were tested, but only test data of the worst mode was presented in this report.		

4.3 Test Setups

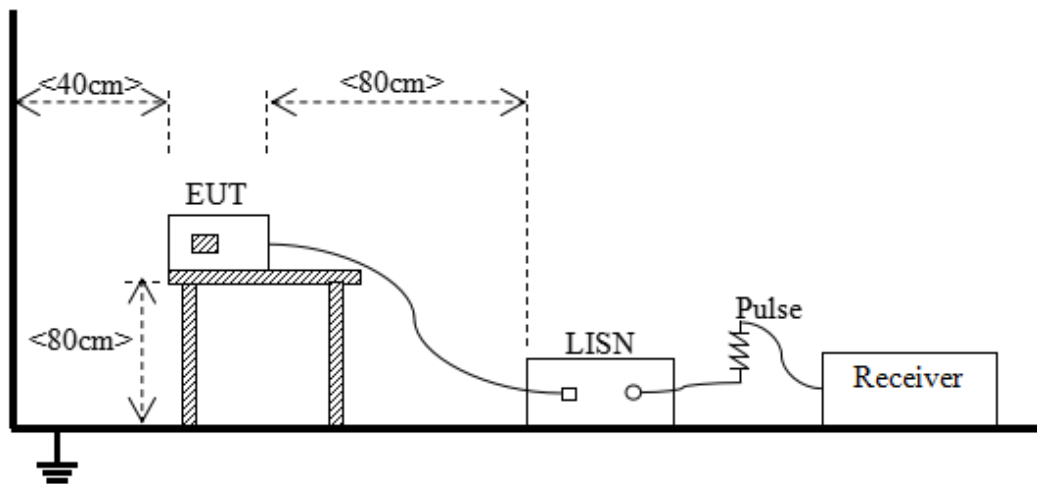
Test Setup 1



Radiated Emission (30 MHz-1 GHz)



Radiated Emission (above 1 GHz)

Test Setup 2

Conducted Emissions, AC Ports

5 TEST ITEMS

5.1 Emission Tests

5.1.1 Radiated Emission

5.1.1.1 Limit

Frequency range (MHz)	Class B (at 3 m)		Class A (at 3 m)
	Field Strength ($\mu\text{V/m}$)	Field Strength (dB $\mu\text{V/m}$)	Field Strength (dB $\mu\text{V/m}$)
30 - 88	100	40	49.5
88 - 216	150	43.5	54
216 - 960	200	46	56.9
Above 960	500	54	60

NOTE:

- 1) Field Strength (dB $\mu\text{V/m}$) = $20 \cdot \log [\text{Field Strength } (\mu\text{V/m})]$.
- 2) In the emission tables above, the tighter limit applies at the band edges.
- 3) For 30 MHz to 1000 MHz, the CISPR quasi-peak is employed.

For above 1000 MHz, according to the requirements of FCC 15.35, unless otherwise specified, the limit on peak radio frequency emissions is 20 dB above the maximum permitted average emission limit applicable to the equipment under test.

Frequency range (GHz)	Class B (at 3 m)			Class A (at 3 m)	
	Field Strength ($\mu\text{V/m}$)	Field Strength Average (dB $\mu\text{V/m}$)	Field Strength Peak (dB $\mu\text{V/m}$)	Field Strength Average (dB $\mu\text{V/m}$)	Field Strength Peak (dB $\mu\text{V/m}$)
1 - F_M	500	54	74	60	80

Note 1: The highest measurement frequency, F_M , in GHz, shall be determined as next Table.

Note 2: Average Class A limit at 3m L_{3m} is determined by the following conversion formula:

$$L_{3m} = L_{10m} + 20 \cdot \log(d_{10m}/d_{3m})$$
Where:
 L_{3m} is Average Class A limit at 3m;
 L_{10m} is Average Class A limit at 10m;
 d_{10m} is Measurement distance in 10m;
 d_{3m} is Measurement distance in 3m.
For this case: $L_{3m} = 49.5 + 20 \cdot \log(10/3) = 60$ (dB $\mu\text{V/m}$).

Highest internal frequency (F_X)	Highest measurement frequency (F_M)
$F_X \leq 108 \text{ MHz}$	1 GHz
$108 \text{ MHz} \leq F_X \leq 500 \text{ MHz}$	2 GHz
$500 \text{ MHz} \leq F_X \leq 1 \text{ GHz}$	5 GHz
$F_X \geq 1 \text{ GHz}$	$5 * F_X$ or 40 GHz, whichever is lower.
Note: F_X is Highest frequency generated or used in the device or on which the device operates or tunes.	

5.1.1.2 Test Setup

Refer to 4.3 section (test setup 1) for radiated emission test, the photo of test setup please refer to ANNEX B.

5.1.1.3 Test Procedure

All Radiated Emission tests were performed in X, Y, Z axis direction. And only the worst axis test condition was recorded in this test report.

An initial pre-scan was performed in the chamber using the EMI Receiver in peak detection mode. Quasi-peak measurements were conducted based on the peak sweep graph. The EUT was measured by Bi-Log antenna with 2 orthogonal polarities.

The measurement frequency range is from 30 MHz to the 5th harmonic of the maximum frequency of the EUT internal source. The Turn Table is actuated to turn from 0° to 360° , and both horizontal and vertical polarizations of the Test Antenna are used to find the maximum radiated power. Mid channels on all channel bandwidth verified. Only the worst RB size/offset presented.

Use the following spectrum analyzer settings:

Span = wide enough to fully capture the emission being measured

RBW = 1 MHz for $f \geq 1 \text{ GHz}$, 100 kHz for $f < 1 \text{ GHz}$

VBW $\geq$ RBW

Sweep = auto

Detector function = peak for $f < 1 \text{ GHz}$, peak & RMS Average for $f \geq 1 \text{ GHz}$

Trace = max hold

5.1.1.4 Test Result and Test Equipment List

Please refer to ANNEX A.1.

NOTE:

1. Results (dB μ V/m) = Reading (dB μ V) + Factor (dB/m)

The reading level is calculated by software which is not shown in the sheet

2. Factor (dB/m) = Antenna Factor (dB/m) + Cable Factor (dB) – Amplifier Gain (dB)

3. Margin = Limit - Results

5.1.2 Conducted Emission, AC Ports

5.1.2.1 Test Limit

Frequency range (MHz)	Class A	
	Quasi-peak (dB μ V)	Average (dB μ V)
0.15 - 0.50	79	66
0.50 - 30	73	60

Frequency range (MHz)	Class B	
	Quasi-peak (dB μ V)	Average (dB μ V)
0.15 - 0.50	66 to 56	56 to 46
0.50 - 5	56	46
5 - 30	60	50

NOTE:

- 1) The lower limit shall apply at the band edges.
- 2) The limit decreases linearly with the logarithm of the frequency in the range 0.15 - 0.50 MHz.

5.1.2.2 Test Setup

Refer to 4.3 section test (test setup 2) for conducted emission, the photo of test setup please refer to ANNEX B.

5.1.2.3 Test Procedure

The EUT is connected to the power mains through a LISN which provides 50 Ω /50 μ H of coupling impedance for the measuring instrument. The test frequency range is from 150 kHz to 30 MHz. The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels that are more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed.

Devices subject to Part 15 must be tested for all available U.S. voltages and frequencies (such as a nominal 120 VAC, 50/60 Hz and 240 VAC, 50/60 Hz) for which the device is capable of operation. A device rated for 50/60 Hz operation need not be tested at both frequencies provided the radiated and line conducted emissions are the same at both frequencies.

Use the following spectrum analyzer settings:

RBW = 9 kHz

VBW $\geq$ RBW

Sweep = 10ms

Detector function = peak & Average

Trace = max hold

5.1.2.4 Test Result and Test Equipment List

Please refer to ANNEX A.2.

NOTE:

1. Results (dB μ V) = Reading (dB μ V) + Factor (dB)

The reading level is calculated by software which is not shown in the sheet

2. Factor = Insertion loss + Cable loss

3. Margin = Limit - Results

ANNEX A TEST RESULTS

A.1 Radiated Emission

Note 1: The symbol of "--" in the table which means not application.

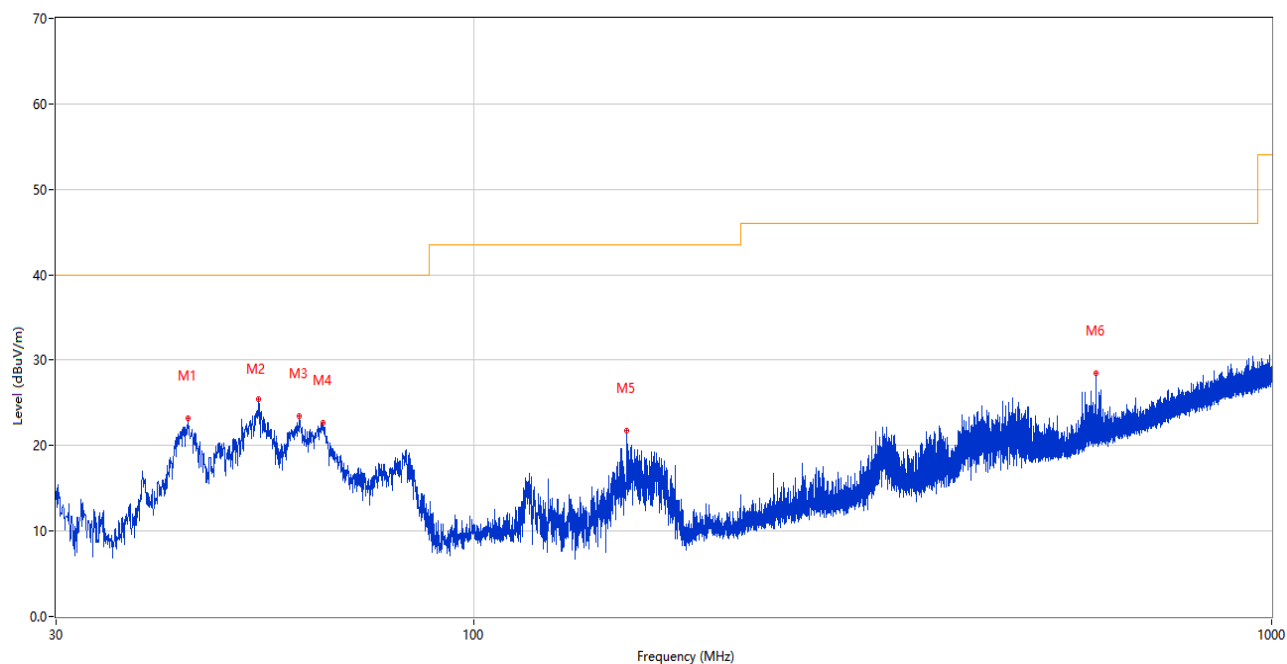
Note 2: For the test data above 1 GHz, according the ANSI C63.4-2014, where limits are specified for both average and peak (or quasi-peak) detector functions, if the peak (or quasi-peak) measured value complies with the average limit, it is unnecessary to perform an average measurement.

Note 3: The Radiated Emission is required to be investigated to the upper frequency of 5th harmonic of the highest internal frequency of EUT or 40 GHz, whichever is lower. The test results above 18GHz are only noise and are not recorded in the report.

Sample No.	S03	Temperature	21.7℃
Humidity	40%RH	Pressure	101kPa
Test Engineer	He Shichang	Test Date	2025.02.11

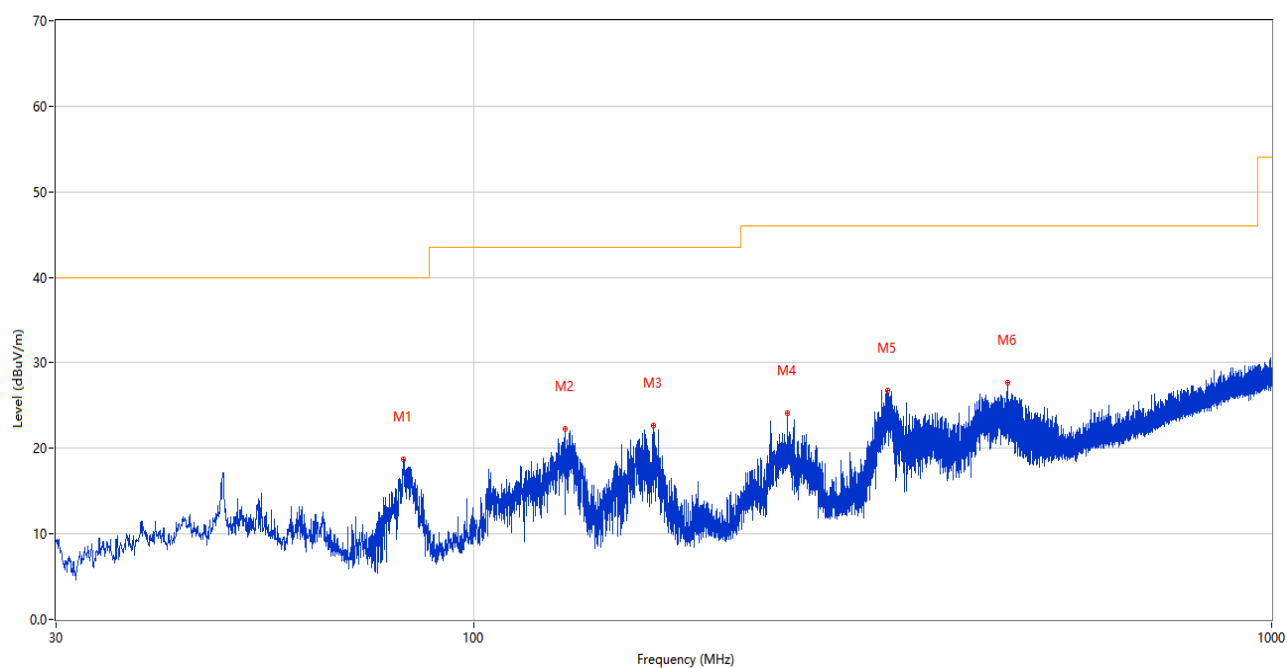
Test Mode 3

1) Test Antenna Vertical, 30 MHz – 1 GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	43.871	23.15	-25.47	40.0	16.85	Peak	81.00	100	Vertical	Pass
2	53.765	25.41	-25.08	40.0	14.59	Peak	75.00	100	Vertical	Pass
3	60.507	23.41	-26.51	40.0	16.59	Peak	43.00	100	Vertical	Pass
4	64.871	22.71	-26.56	40.0	17.29	Peak	81.00	100	Vertical	Pass
5	155.760	21.77	-29.73	43.5	21.73	Peak	360.00	100	Vertical	Pass
6	602.446	28.51	-15.85	46.0	17.49	Peak	202.00	100	Vertical	Pass

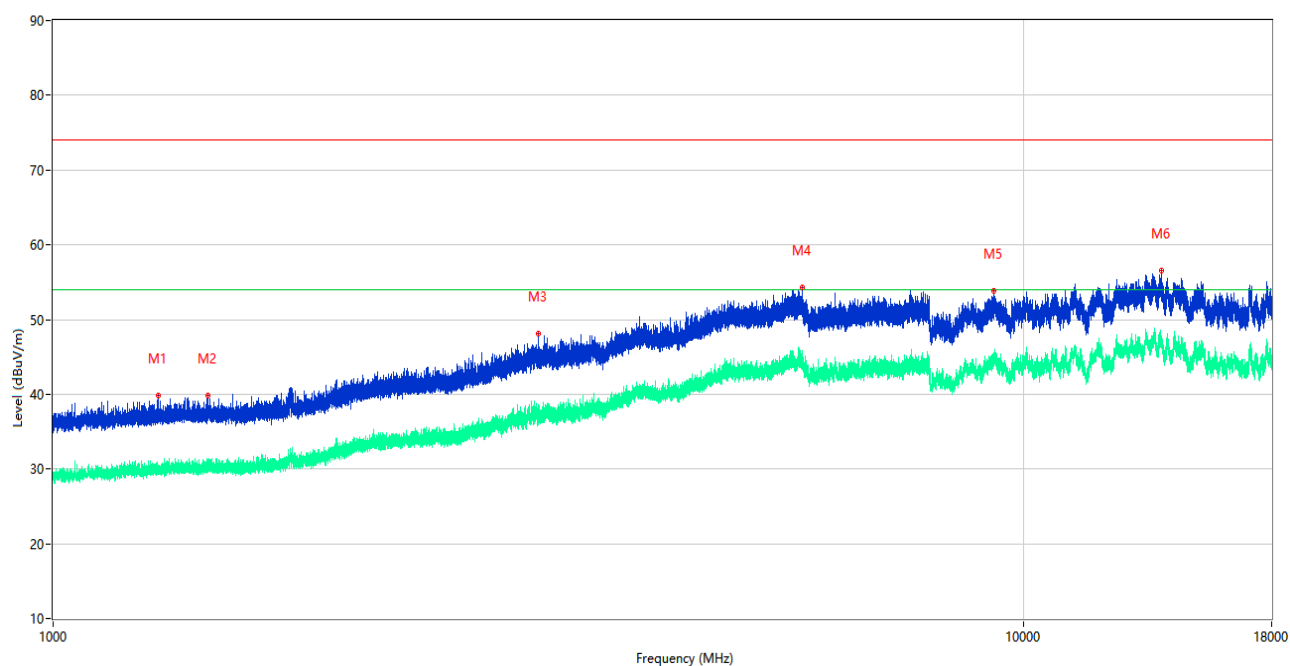
2) Test Antenna Horizontal, 30 MHz – 1 GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	81.604	18.73	-30.57	40.0	21.27	Peak	113.00	200	Horizontal	Pass
2	130.201	22.28	-30.11	43.5	21.22	Peak	149.00	200	Horizontal	Pass
3	167.837	22.62	-29.18	43.5	20.88	Peak	101.00	200	Horizontal	Pass
4	247.571	24.13	-25.04	46.0	21.87	Peak	60.00	100	Horizontal	Pass
5	330.215	26.82	-22.76	46.0	19.18	Peak	186.00	100	Horizontal	Pass
6	467.567	27.63	-19.51	46.0	18.37	Peak	255.00	100	Horizontal	Pass

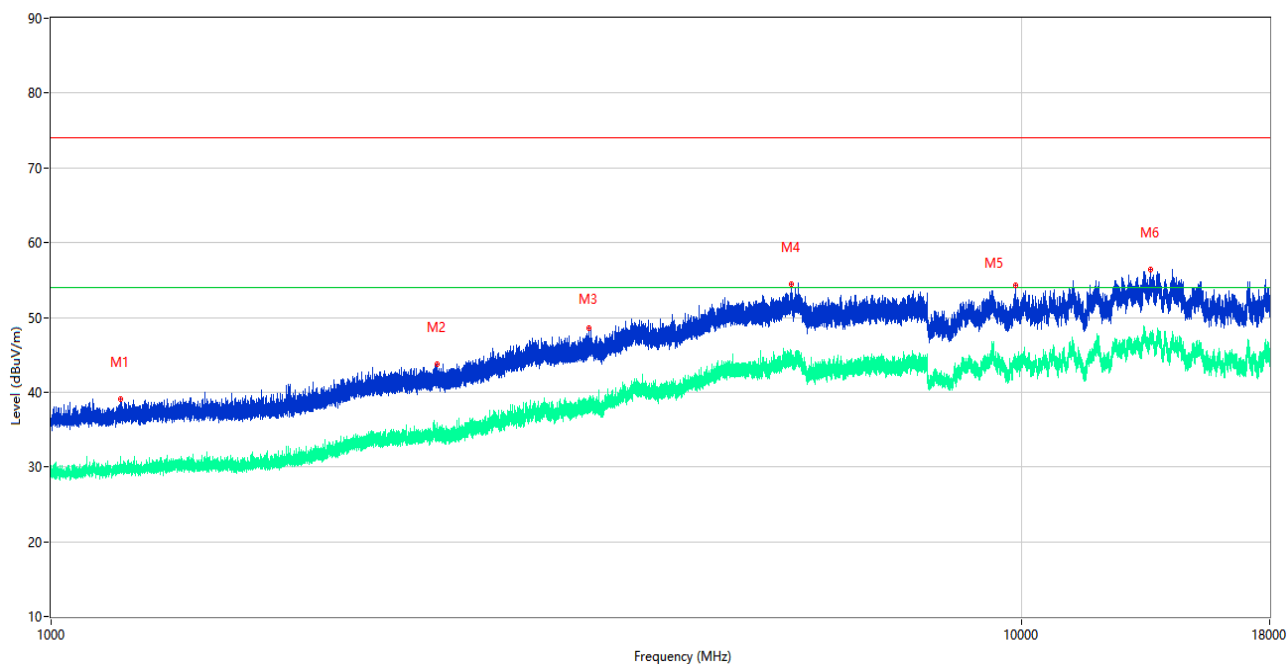
Equipment Information						
Equipment Name	Supplier	Model	Serial No.	Cal. Date	Cal. Due	Use
Frequency Below 1 GHz						
EMI Receiver	Keysight	N9038A	MY55330120	2024.08.01	2025.07.31	☒
Amplifier (30-1GHz)	COM-MV	ZT30-1000M	B2017119081	2024.11.28	2025.11.27	☒
Test Antenna- Bi-Log	SCHWARZB ECK	VULB 9168	9168-00867	2022.04.12	2025.04.11	☒
Anechoic Chamber (#2)	YiHeng	9m*6m*6m	142	2024.07.21	2027.07.20	☒
Description	Supplier	Name	Version	/		Use
Test Software	BALUN	BL410-E	V22.930	/		☒

3) Test Antenna Vertical, 1 GHz – 18 GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	1283.010	39.87	-15.71	74.0	34.13	Peak	83.00	100	Vertical	Pass
1**	1283.010	30.26	-15.71	54.0	23.74	AV	83.00	100	Vertical	Pass
2	1444.600	39.76	-15.52	74.0	34.24	Peak	93.00	100	Vertical	Pass
2**	1444.600	30.20	-15.52	54.0	23.80	AV	93.00	100	Vertical	Pass
3	3164.630	48.07	-6.15	74.0	25.93	Peak	54.00	100	Vertical	Pass
3**	3164.630	36.40	-6.15	54.0	17.60	AV	54.00	100	Vertical	Pass
4	5919.240	54.34	1.71	74.0	19.66	Peak	58.00	100	Vertical	Pass
4**	5919.240	44.91	1.71	54.0	9.09	AV	58.00	100	Vertical	Pass
5	9311.500	53.86	2.19	74.0	20.14	Peak	259.00	100	Vertical	Pass
5**	9311.500	44.39	2.19	54.0	9.61	AV	259.00	100	Vertical	Pass
6	13848.001	56.55	5.20	74.0	17.45	Peak	50.00	100	Vertical	Pass
6**	13848.001	46.89	5.20	54.0	7.11	AV	50.00	100	Vertical	Pass

4) Test Antenna Horizontal, 1 GHz – 18 GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	1179.270	39.14	-15.84	74.0	34.86	Peak	217.00	100	Horizontal	Pass
1**	1179.270	30.73	-15.84	54.0	23.27	AV	217.00	100	Horizontal	Pass
2	2496.560	43.72	-10.41	74.0	30.28	Peak	132.00	100	Horizontal	Pass
2**	2496.560	34.56	-10.41	54.0	19.44	AV	132.00	100	Horizontal	Pass
3	3578.290	48.52	-4.70	74.0	25.48	Peak	298.00	100	Horizontal	Pass
3**	3578.290	37.90	-4.70	54.0	16.10	AV	298.00	100	Horizontal	Pass
4	5786.580	54.47	1.99	74.0	19.53	Peak	360.00	100	Horizontal	Pass
4**	5786.580	43.87	1.99	54.0	10.13	AV	360.00	100	Horizontal	Pass
5	9847.500	54.34	1.04	74.0	19.66	Peak	324.00	100	Horizontal	Pass
5**	9847.500	44.72	1.04	54.0	9.28	AV	324.00	100	Horizontal	Pass
6	13577.500	56.45	4.73	74.0	17.55	Peak	168.00	100	Horizontal	Pass
6**	13577.500	47.55	4.73	54.0	6.45	AV	168.00	100	Horizontal	Pass

Equipment Information						
Equipment Name	Supplier	Model	Serial No.	Cal. Date	Cal. Due	Use
Frequency Above 1 GHz						
EMI Receiver	Keysight	N9038A	MY55330120	2024.08.01	2025.07.31	☒
Amplifier (1-12GHz)	Advanced Microwave	WLA652A	1740103	2024.11.28	2025.11.27	☒
Amplifier (0.8-21GHz)	Mini-Circuits	ZVA-213-S+	225321316	2024.11.28	2025.11.27	☒
Test Antenna- Horn	SCHWARZB ECK	BBHA 9120D	01917	2022.06.09	2025.06.08	☒
Anechoic Chamber (#2)	YiHeng	9m*6m*6m	142	2024.07.21	2027.07.20	☒
Description	Supplier	Name	Version	/		Use
Test Software	BALUN	BL410-E	V22.930	/		☒

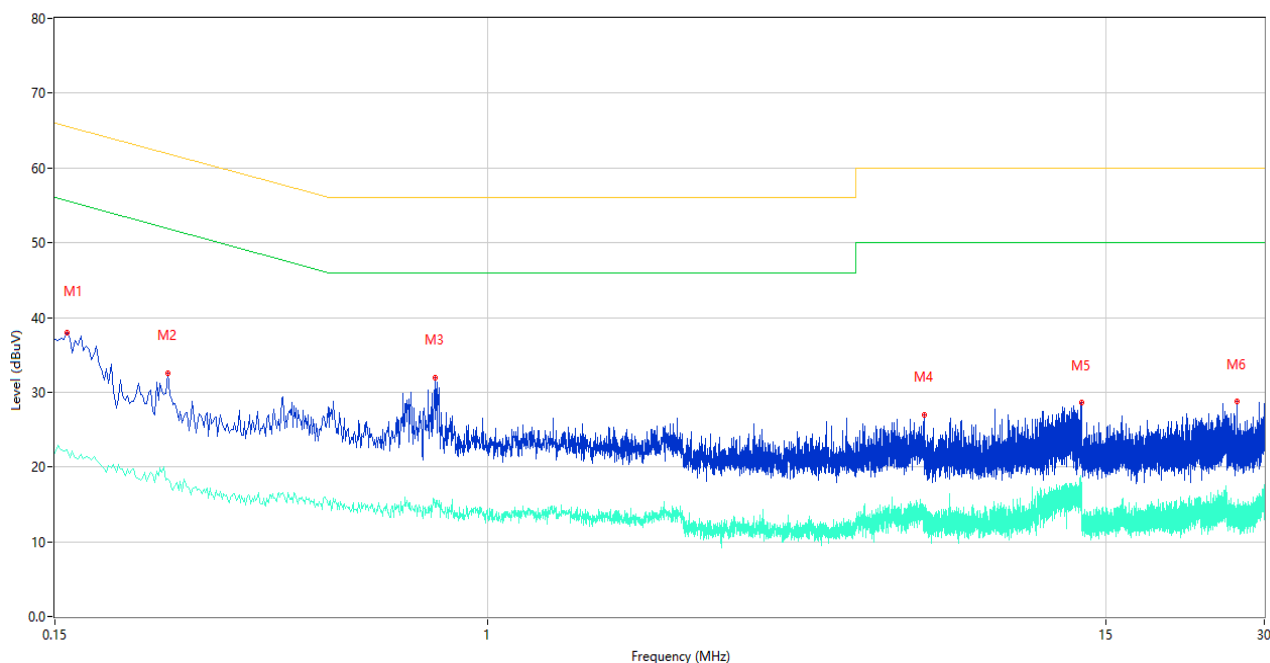
A.2 Conducted Emission, AC Ports

Note: Devices subject to Part 15 must be tested for all available U.S. voltages and frequencies (such as a nominal 120 VAC, 50/60 Hz and 240 VAC, 50/60 Hz) for which the device is capable of operation. So, The configuration 120 VAC, 60 Hz and 240 VAC, 50 Hz were tested respectively, but only the worst configuration (120 VAC, 60 Hz) shown here.

Sample No.	S02	Temperature	24.0℃
Humidity	59%RH	Pressure	101kPa
Test Engineer	Yuan Zhishen	Test Date	2023.07.03

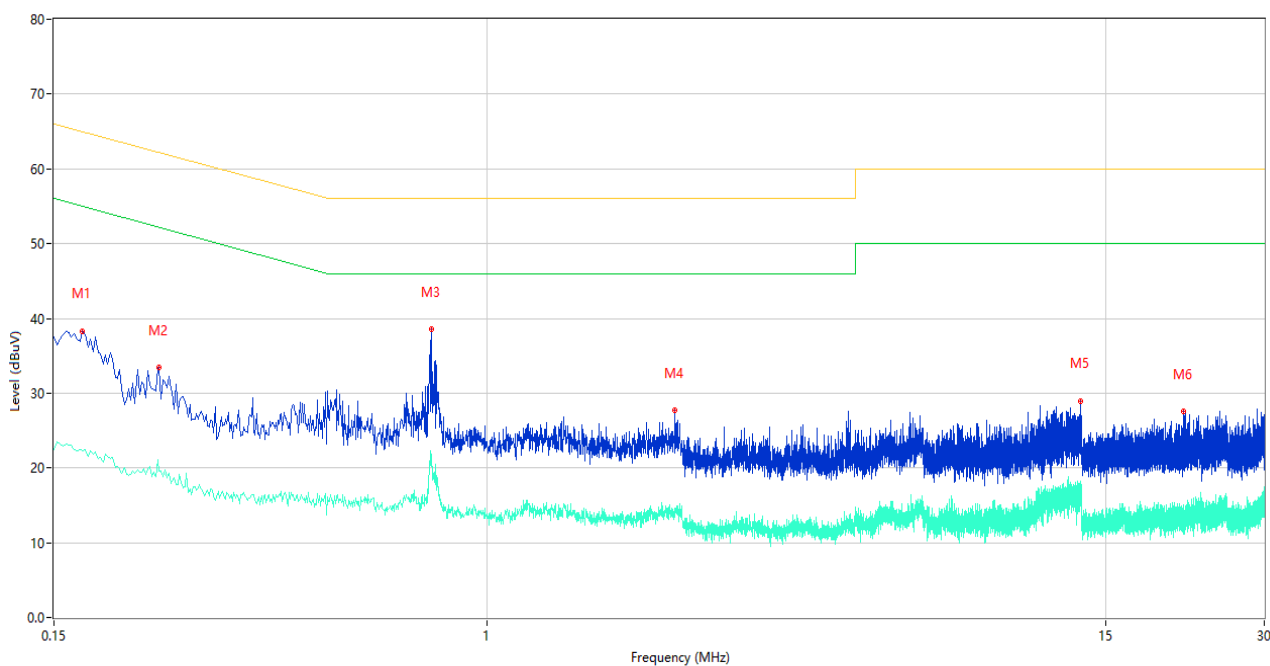
Test Mode 3

1) AC Ports - L Phase



No.	Frequency (MHz)	Results (dBuV)	Factor (dB)	Limit (dBuV)	Margin (dB)	Detector	Line	Verdict
1	0.158	38.03	9.83	65.57	27.54	Peak	L	Pass
1**	0.158	22.28	9.83	55.57	33.29	AV	L	Pass
2	0.246	32.60	9.79	61.89	29.29	Peak	L	Pass
2**	0.246	18.40	9.79	51.89	33.49	AV	L	Pass
3	0.794	31.99	9.53	56.00	24.01	Peak	L	Pass
3**	0.794	15.15	9.53	46.00	30.85	AV	L	Pass
4	6.772	27.03	10.29	60.00	32.97	Peak	L	Pass
4**	6.772	14.64	10.29	50.00	35.36	AV	L	Pass
5	13.494	28.61	10.20	60.00	31.39	Peak	L	Pass
5**	13.494	15.99	10.20	50.00	34.01	AV	L	Pass
6	26.652	28.77	10.94	60.00	31.23	Peak	L	Pass
6**	26.652	14.08	10.94	50.00	35.92	AV	L	Pass

2) AC Ports - N Phase



No.	Frequency (MHz)	Results (dBuV)	Factor (dB)	Limit (dBuV)	Margin (dB)	Detector	Line	Verdict
1	0.170	38.33	9.82	64.96	26.63	Peak	N	Pass
1**	0.170	22.35	9.82	54.96	32.61	AV	N	Pass
2	0.238	33.49	9.79	62.17	28.68	Peak	N	Pass
2**	0.238	19.60	9.79	52.17	32.57	AV	N	Pass
3	0.784	38.51	9.58	56.00	17.49	Peak	N	Pass
3**	0.784	21.89	9.58	46.00	24.11	AV	N	Pass
4	2.270	27.74	10.23	56.00	28.26	Peak	N	Pass
4**	2.270	13.90	10.23	46.00	32.10	AV	N	Pass
5	13.416	28.98	10.52	60.00	31.02	Peak	N	Pass
5**	13.416	16.11	10.52	50.00	33.89	AV	N	Pass
6	21.048	27.58	10.80	60.00	32.42	Peak	N	Pass
6**	21.048	14.24	10.80	50.00	35.76	AV	N	Pass

Equipment Information						
Equipment Name	Supplier	Model	Serial No.	Cal. Date	Cal. Due	Use
EMI Receiver	KEYSIGHT	N9010B	MY57110309	2022.09.09	2023.09.08	☒
LISN	SCHWARZB ECK	NSLK 8127	8127-687	2023.05.16	2024.05.15	☒
ISN	TESEQ	ISN T800	34449	2022.11.11	2023.11.10	☐
ISN	TESEQ	ISN T8-Cat6	53561	2023.04.23	2024.04.22	☐
Shielded Room	YiHeng Electronic Co., Ltd	3.5m*3.1m*2. 8m	112	2022.02.19	2025.02.18	☒
Description	Supplier	Name	Version	/		Use
Test Software	BALUN	BL410-E	V22.930	/		☒

ANNEX B TEST SETUP PHOTOS

Please refer the document “BL-SZ2511007-AE.PDF”.

ANNEX C EUT EXTERNAL PHOTOS

Please refer the document “BL-SZ2511007-AW.PDF”.

ANNEX D EUT INTERNAL PHOTOS

Please refer the document “BL-SZ2511007-AI.PDF”.

Statement

1. The laboratory guarantees the scientificity, accuracy and impartiality of the test, and is responsible for all the information in the report, except the information provided by the customer. The customer is responsible for the impact of the information provided on the validity of the results.
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--END OF REPORT--